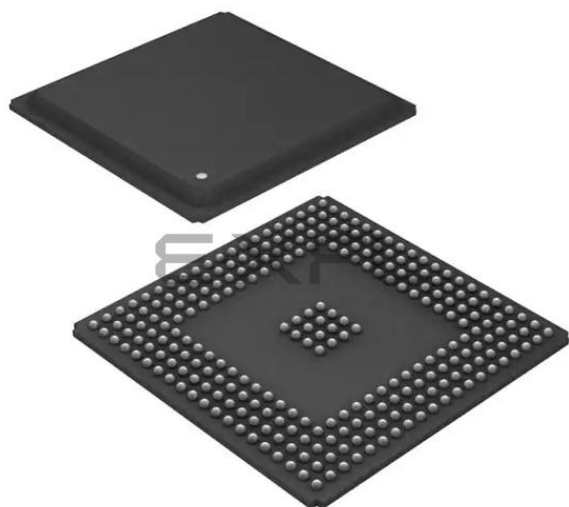




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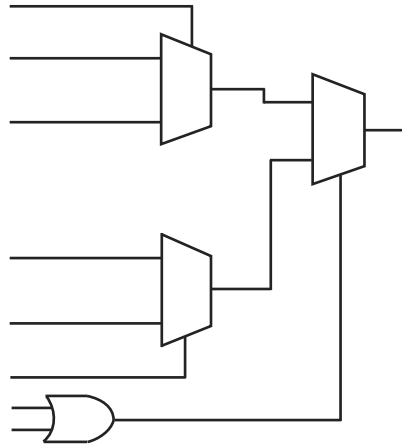
Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	2560
Number of I/O	202
Number of Gates	54000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	272-BBGA
Supplier Device Package	272-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx36-2bgg272

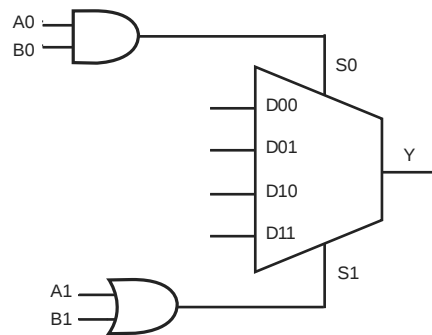
	VCCA = 3.0 V, T _J = 70°C)	79
Table 46	Configuration of Unused I/Os	84
Table 47	PL44	86
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Table 49	PL84	90
Table 50	PQ 100	93
Table 51	PQ144	97
Table 52	PQ160	102
Table 53	PQ208	107
Table 54	PQ240	113
Table 55	VQ80	120
Table 56	VQ100	123
Table 57	TQ176	126
Table 58	CQ208	132
Table 59	CQ256	138
Table 60	BG272	145
Table 61	PG132	153
Table 62	CQ172	158

Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Maximum Flip-Flops	147	273	516	928	1,410	1,822
Clocks	1	1	2	2	2	6
User I/O (maximum)	57	69	104	140	176	202
PCI	–	–	–	–	Yes	Yes
Boundary Scan Test (BST)	–	–	–	–	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	–
PQFP	100	100	100, 144, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	–	–
TQFP	–	–	176	176	176	–
CQFP	–	–	–	172	–	208, 256
PBGA	–	–	–	–	–	272
CPGA	–	–	132	–	–	–

Figure 2 • 42MX C-Module Implementation

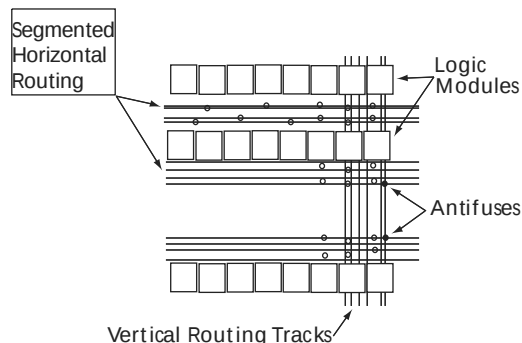
The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in Figure 4, page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

Figure 3 • 42MX C-Module Implementation

3.2.3.3 Antifuse Structures

An antifuse is a “normally open” structure. The use of antifuses to implement a programmable logic device results in highly testable structures as well as efficient programming algorithms. There are no pre-existing connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed and individual circuit structures to be tested, which can be done before and after programming. For instance, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

Figure 7 • MX Routing Structure



3.2.4 Clock Networks

The 40MX devices have one global clock distribution network (CLK). A signal can be put on the CLK network by being routed through the CLKBUF buffer.

In 42MX devices, there are two low-skew, high-fanout clock distribution networks, referred to as CLKA and CLKB. Each network has a clock module (CLKMOD) that can select the source of the clock signal from any of the following (Figure 8, page 11):

- Externally from the CLKA pad, using CLKBUF buffer
- Externally from the CLKB pad, using CLKBUF buffer
- Internally from the CLKINTA input, using CLKINT buffer
- Internally from the CLKINTB input, using CLKINT buffer

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel.

Clock input pads in both 40MX and 42MX devices can also be used as normal I/Os, bypassing the clock networks.

The A42MX36 device has four additional register control resources, called quadrant clock networks (Figure 9, page 11). Each quadrant clock provides a local, high-fanout resource to the contiguous logic modules within its quadrant of the device. Quadrant clock signals can originate from specific I/O pins or from the internal array and can be used as a secondary register clock, register clear, or output enable.

Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the *.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the *AC225: Programming Antifuse Devices* application note and the *Silicon Sculptor 3 Programmers User Guide*.

3.3.4 Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

Table 6 • Voltage Support of MX Devices

Device	VCC	VCCA	VCCI	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0 V	–	–	5.5 V	5.0 V
	3.3 V	–	–	3.6 V	3.3 V
42MX	–	5.0 V	5.0 V	5.5 V	5.0 V
	–	3.3 V	3.3 V	3.6 V	3.3 V
	–	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the *AC291: 42MX Family Devices Power-Up Behavior*.

3.3.5 Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

3.3.6 Transient Current

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{ja} (^\circ\text{C/W})} = \frac{150^\circ\text{C} - 70^\circ\text{C}}{(28^\circ\text{C})/\text{W}} = 2.86\text{W}$$

EQ 5

The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{jc} (^\circ\text{C/W})} = \frac{150^\circ\text{C} - 125^\circ\text{C}}{(6.3^\circ\text{C})/\text{W}} = 3.97\text{W}$$

EQ 6

Table 27 • Package Thermal Characteristics

Plastic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min.	2.5 m/s 500 ft/min.	
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	$^\circ\text{C/W}$
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	$^\circ\text{C/W}$
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	$^\circ\text{C/W}$
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	$^\circ\text{C/W}$
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	$^\circ\text{C/W}$
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	$^\circ\text{C/W}$
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	$^\circ\text{C/W}$
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	$^\circ\text{C/W}$
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	$^\circ\text{C/W}$
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	$^\circ\text{C/W}$
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	$^\circ\text{C/W}$
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	$^\circ\text{C/W}$

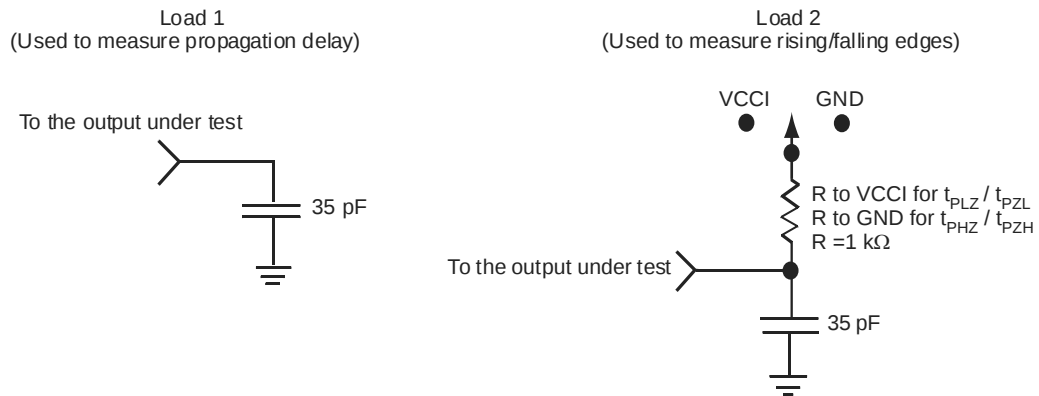
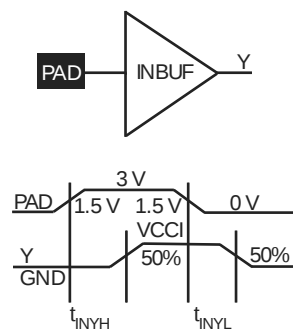
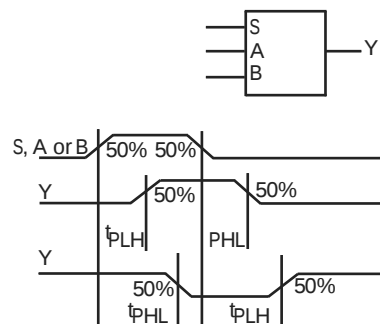
Figure 22 • AC Test Loads**Figure 23 • Input Buffer Delays****Figure 24 • Module Delays**

Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH		0.7		0.8		0.9		1.1		1.5		ns
t _{INYL}	Pad-to-Y LOW		0.6		0.7		0.8		1.0		1.3		ns
Input Module Predicted Routing Delays ¹													
t _{IRD1}	FO = 1 Routing Delay		2.1		2.4		2.2		3.2		4.5		ns
t _{IRD2}	FO = 2 Routing Delay		2.6		3.0		3.4		4.0		5.6		ns
t _{IRD3}	FO = 3 Routing Delay		3.1		3.6		4.1		4.8		6.7		ns
t _{IRD4}	FO = 4 Routing Delay		3.6		4.2		4.8		5.6		7.8		ns
t _{IRD8}	FO = 8 Routing Delay		5.7		6.6		7.5		8.8		12.4		ns
Global Clock Network													
t _{CKH}	Input Low to HIGH	FO = 16 FO = 128	4.6 4.6		5.3 5.3		6.0 6.0		7.0 7.0		9.8 9.8		ns
t _{CKL}	Input High to LOW	FO = 16 FO = 128	4.8 4.8		5.6 5.6		6.3 6.3		7.4 7.4		10.4 10.4		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 16 FO = 128	2.2 2.4	2.6 2.7		2.9 3.1		3.4 3.6		4.8 5.1		ns	
t _{PWL}	Minimum Pulse Width LOW	FO = 16 FO = 128	2.2 2.4	2.6 2.7		2.9 3.01		3.4 3.6		4.8 5.1		ns	
t _{CKSW}	Maximum Skew	FO = 16 FO = 128	0.4 0.5		0.5 0.6		0.5 0.7		0.6 0.8		0.8 1.2		ns
t _P	Minimum Period	FO = 16 FO = 128	4.7 4.8	5.4 5.6		6.1 6.3		7.2 7.5		10.0 10.4		ns	
f _{MAX}	Maximum Frequency	FO = 16 FO = 128	188 181		175 168		160 154		139 134		83 80		MHz

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays ¹													
t _{IRD1}	FO = 1 Routing Delay		2.9		3.3		3.8		4.5		6.3		ns
t _{IRD2}	FO = 2 Routing Delay		3.6		4.2		4.8		5.6		7.8		ns
t _{IRD3}	FO = 3 Routing Delay		4.4		5.0		5.7		6.7		9.4		ns
t _{IRD4}	FO = 4 Routing Delay		5.1		5.9		6.7		7.8		11.0		ns
t _{IRD8}	FO = 8 Routing Delay		8.0		9.3		10.5		12.4		17.2		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 16 FO = 128	6.4 6.4		7.4 7.4		8.4 8.4		9.9 9.9		13.8 13.8		ns
t _{CKL}	Input HIGH to LOW	FO = 16 FO = 128	6.8 6.8		7.8 7.8		8.9 8.9		10.4 10.4		14.6 14.6		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 16 FO = 128	3.1 3.3		3.6 3.8		4.1 4.3		4.8 5.1		6.7 7.1		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 16 FO = 128	3.1 3.3		3.6 3.8		4.1 4.3		4.8 5.1		6.7 7.1		ns
t _{CKSW}	Maximum Skew	FO = 16 FO = 128	0.6 0.8		0.6 0.9		0.7 1.0		0.8 1.2		1.2 1.6		ns
t _P	Minimum Period	FO = 16 FO = 128	6.5 6.8		7.5 7.8		8.5 8.9		10.1 10.4		14.1 14.6		ns
f _{MAX}	Maximum Frequency	FO = 16 FO = 128	113 109		105 101		96 92		83 80		50 48		MHz
TTL Output Module Timing ⁴													
t _{DLH}	Data-to-Pad HIGH		4.7		5.4		6.1		7.2		10.0		ns
t _{DHL}	Data-to-Pad LOW		5.6		6.4		7.3		8.6		12.0		ns
t _{ENZH}	Enable Pad Z to HIGH		5.2		6.0		6.9		8.1		11.3		ns
t _{ENZL}	Enable Pad Z to LOW		6.6		7.6		8.6		10.1		14.1		ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9		ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7		ns
d _{TLH}	Delta LOW to HIGH		0.03		0.03		0.04		0.04		0.06		ns/pF
d _{THL}	Delta HIGH to LOW		0.04		0.04		0.05		0.06		0.08		ns/pF

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.4		3.8		5.5		6.4		9.0	ns
t _{DHL}	Data-to-Pad LOW		4.1		4.5		4.2		5.0		7.0	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t _{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t _{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t _{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t _{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units	
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Logic Module Propagation Delays ¹													
t _{PD1}	Single Module	1.4		1.5		1.7		2.0		2.8			ns
t _{CO}	Sequential Clock-to-Q	1.4		1.6		1.8		2.1		3.0			ns
t _{GO}	Latch G-to-Q	1.4		1.5		1.7		2.0		2.8			ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q	1.6		1.7		2.0		2.3		3.3			ns
Logic Module Predicted Routing Delays ²													
t _{RD1}	FO = 1 Routing Delay	0.8		0.9		1.0		1.2		1.6			ns
t _{RD2}	FO = 2 Routing Delay	1.0		1.2		1.3		1.5		2.1			ns

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		11.3		12.5		14.2		16.7		23.3	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. For dual-module macros use tPD1 + tRD1 + taped, to + tRD1 + taped, or tPD1 + tRD1 + tusk, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions ¹												
t _{PD}	Internal Array Module Delay		1.2		1.3		1.5		1.8		2.5	ns
t _{PDD}	Internal Decode Module Delay		1.4		1.6		1.8		2.1		3.0	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		0.8		0.9		1.0		1.2		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.0		1.2		1.3		1.5		2.1	ns
t _{RD3}	FO = 3 Routing Delay		1.3		1.4		1.6		1.9		2.6	ns
t _{RD4}	FO = 4 Routing Delay		1.5		1.7		1.9		2.2		3.1	ns
t _{RD5}	FO = 8 Routing Delay		2.4		2.7		3.0		3.6		5.0	ns
Logic Module Sequential Timing ^{3, 4}												
t _{CO}	Flip-Flop Clock-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch Gate-to-Output		1.2		1.3		1.5		1.8		2.5	ns
t _{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RO}	Flip-Flop (Latch) Reset-to-Output		1.4		1.6		1.8		2.1		2.9	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.3		6.5		9.0		ns

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵ (Continued)												
t _{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t _{GLH}	G-to-Pad HIGH		2.9		3.3		3.7		4.4		6.1	ns
t _{GHL}	G-to-Pad LOW		2.9		3.3		3.7		4.4		6.1	ns
t _{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.07		0.08		0.09		0.10		0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.07		0.08		0.09		0.10		0.14	ns/pF

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Synchronous SRAM Operations (continued)												
t _{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RENSU}	Read Enable Set-Up	0.9		1.0		1.1		1.3		1.8		ns
t _{RENH}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t _{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t _{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{BENS}	Block Enable Set-Up	3.9		4.3		4.9		5.7		8.0		ns
t _{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
Asynchronous SRAM Operations												
t _{RPD}	Asynchronous Access Time		11.3		12.6		14.3		16.8		23.5	ns
t _{RDADV}	Read Address Valid	12.3		13.7		15.5		18.2		25.5		ns
t _{ADSU}	Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns
t _{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RENSUA}	Read Enable Set-Up to Address Valid	0.9		1.0		1.1		1.3		1.8		ns
t _{RENHA}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t _{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t _{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{DOH}	Data Out Hold Time		1.8		2.0		2.1		2.5		3.5	ns
Input Module Propagation Delays												
t _{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.1		3.0	ns
t _{INGO}	Input Latch Gate-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t _{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns

Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
6	I/O
7	I/O
8	I/O
9	GNDQ
10	GNDI
11	NC
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	VSV
19	VCC
20	VCCI
21	NC
22	I/O
23	I/O
24	I/O
25	I/O
26	I/O
27	I/O
28	GND
29	GNDI
30	NC
31	I/O
32	I/O
33	I/O
34	I/O
35	I/O
36	I/O
37	BININ
38	BINOUT
39	I/O
40	I/O
41	I/O
42	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
52	VCCI
53	I/O
54	WD, I/O
55	WD, I/O
56	I/O
57	SDI, I/O
58	I/O
59	VCCA
60	GND
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	VCCI
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	VCCA
86	I/O
87	I/O
88	VCCA

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
237	GND
238	MODE
239	VCCA
240	GND

Figure 46 • VQ80

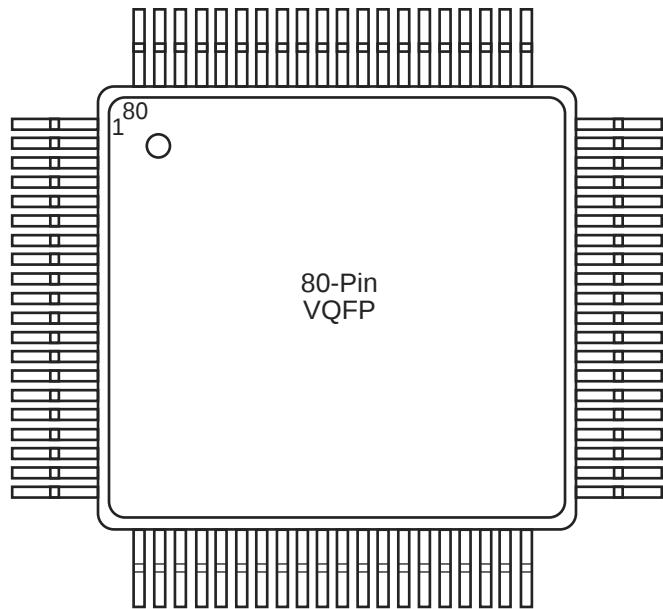


Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	NC	I/O
3	NC	I/O
4	NC	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O

Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
93	I/O	I/O
94	GND	GND
95	I/O	I/O
96	I/O	I/O
97	I/O	I/O
98	I/O	I/O
99	I/O	I/O
100	DCLK, I/O	DCLK, I/O

Figure 48 • TQ176

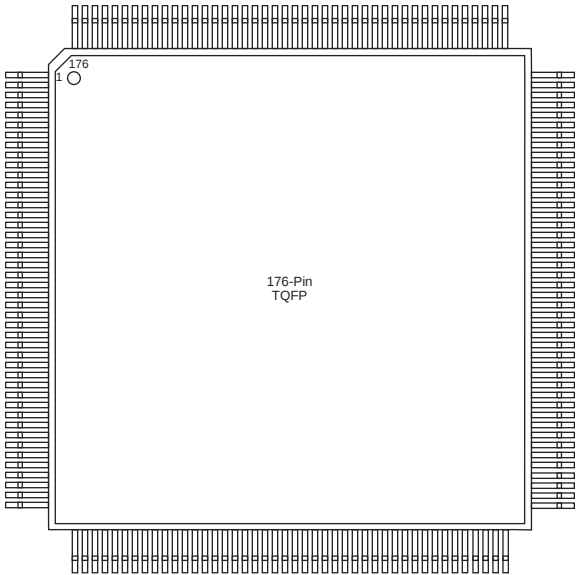


Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	GND	GND	GND
2	MODE	MODE	MODE
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	NC	NC	I/O
9	I/O	I/O	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
170	VCCA
171	I/O
172	I/O
173	I/O
174	I/O
175	I/O
176	I/O
177	I/O
178	I/O
179	I/O
180	GND
181	I/O
182	I/O
183	I/O
184	I/O
185	I/O
186	I/O
187	I/O
188	MODE
189	VCCA
190	GND
191	NC
192	NC
193	NC
194	I/O
195	DCLK, I/O
196	I/O
197	I/O
198	I/O
199	WD, I/O
200	WD, I/O
201	VCCI
202	I/O
203	I/O
204	I/O
205	I/O
206	GND

Table 62 • CQ172

21	I/O
22	GND
23	VCCI
24	VSV
25	I/O
26	I/O
27	VCC
28	I/O
29	I/O
30	I/O
31	I/O
32	GND
33	I/O
34	I/O
35	I/O
36	I/O
37	GND
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	BININ
45	BINOUT
46	I/O
47	I/O
48	I/O
49	I/O
50	VCCI
51	I/O
52	I/O
53	I/O
54	I/O
55	GND
56	I/O
57	I/O
58	I/O
59	I/O

Table 62 • CQ172

99	I/O
100	I/O
101	I/O
102	I/O
103	GND
104	I/O
105	I/O
106	VKS
107	VPP
108	GND
109	VCCI
110	VSV
111	I/O
112	I/O
113	VCC
114	I/O
115	I/O
116	I/O
117	I/O
118	GND
119	I/O
120	I/O
121	I/O
122	I/O
123	GNDI
124	I/O
125	I/O
126	I/O
127	I/O
128	I/O
129	I/O
130	I/O
131	SDI
132	I/O
133	I/O
134	I/O
135	I/O
136	VCCI
137	I/O